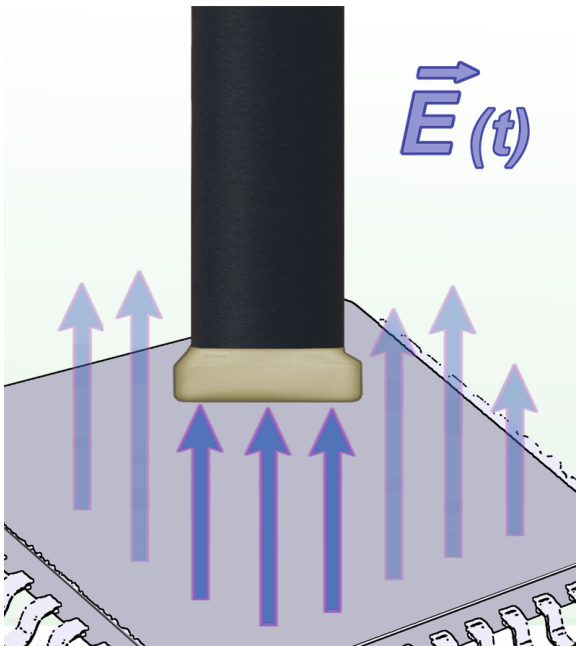


SX-E 03

E-Field Probe 1 GHz up to 10 GHz

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Short description

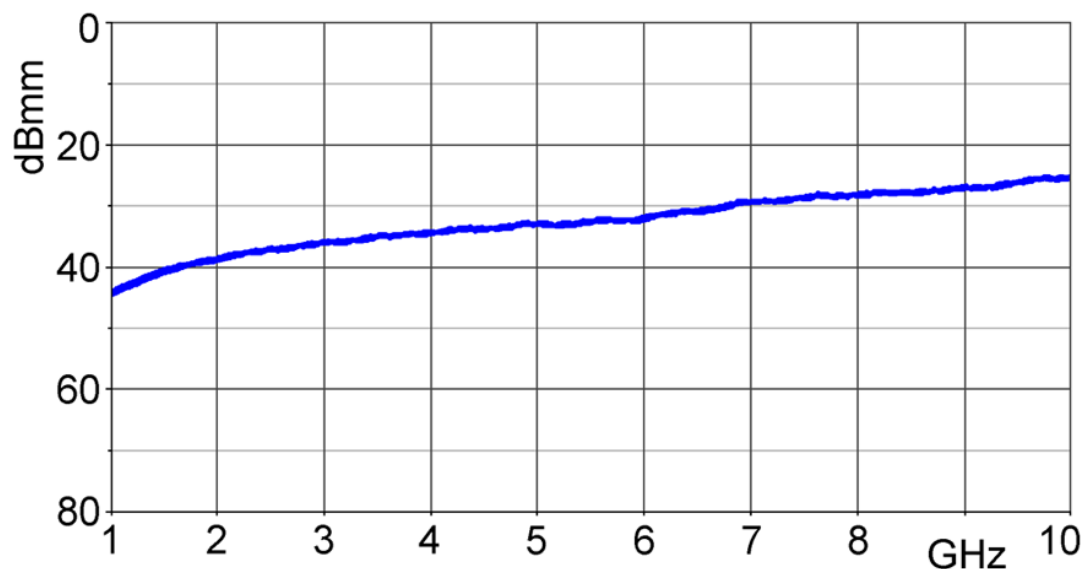
With 4x4 mm dimensions, the electrode on the underside of the probe head of the SX-E 03 is very compact. This allows for the localization of very small E-field sources, e.g. at conducting paths, single components, or on printed circuit boards.

The SX-E 03 is a passive near-field probe. To measure, the probe head is positioned directly onto the measured object, due to higher electrical field strength at the measured object. The near-field probe is small and handy. It has a current attenuating sheath and its upper side is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input.

Technical parameters

Frequency range	1 GHz ... 10 GHz
Probe head dimensions	$\approx (4 \times 4)$ mm
Connector - output	SMA, female, jack

Frequency response [dB μ V] / [dB μ V/mm]

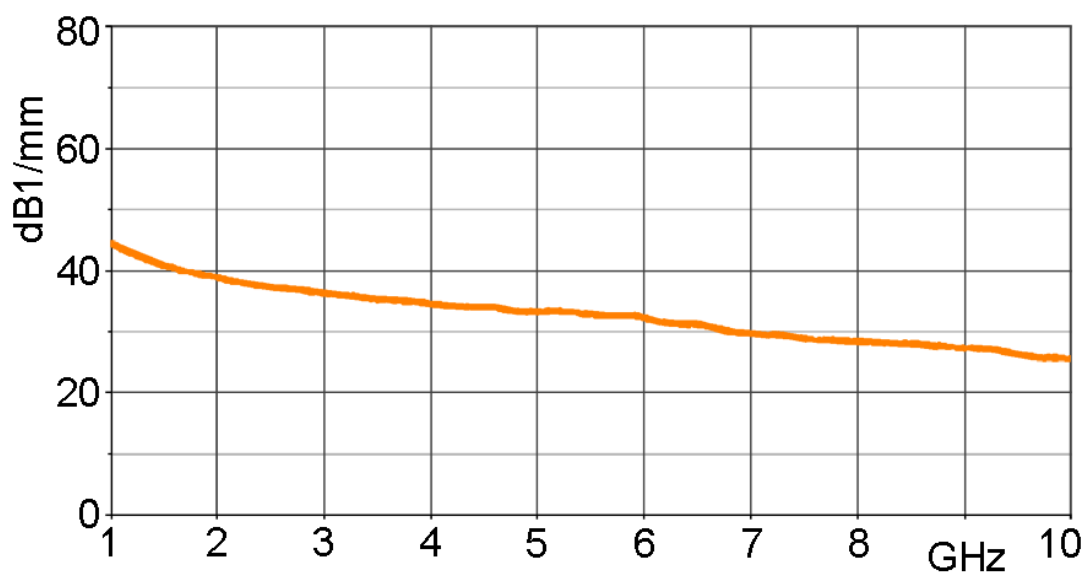


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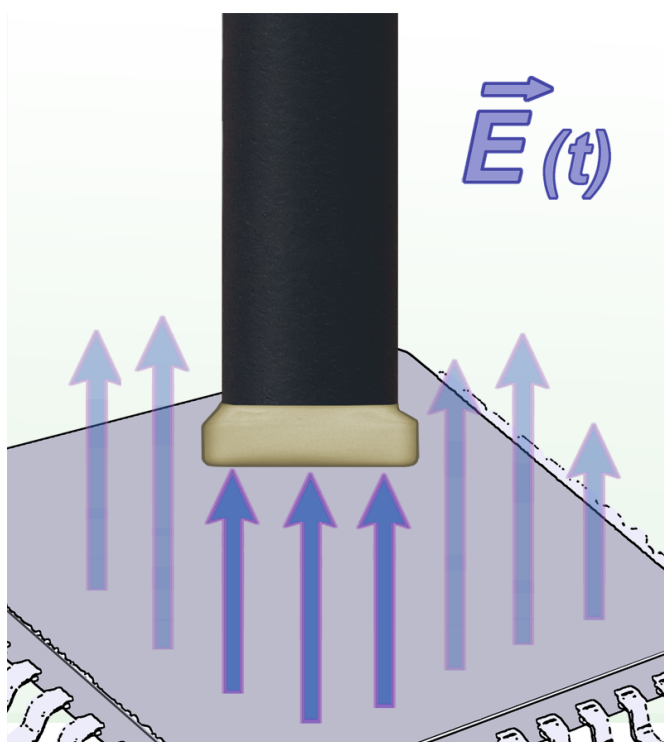
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E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



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Probe head

